


<b>Search Notes</b>  	<b>Application/Control No.</b>  10717942	<b>Applicant(s)/Patent Under Reexamination</b>  BAI ET AL.
	<b>Examiner</b>  Keefer, Michael E	<b>Art Unit</b>  2154

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
709	235	7/3/2007	MEK

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Search	7/6/2007	MEK
Consulted Examiner Joshua Joo	7/3/2007	MEK
Consulted Examiner Adam Weintrop	7/5/2007	MEK

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>